

Date Searched: 6/29/2003

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 (actual or physical or real) same (measur\$6 or extract\$4 or determin\$6 or get\$4 or obtain\$3)

L2 physic same model\$3

L3 bayesian adj interference

Results: 0 hit

L4 bayesian

L5 ((knowledge\$ adj base\$2) or (machine adj learning) or ai or (artificial adj intelligen\$3))

L6 1 and 2 and 4 and 6

Results: 5 hits

L7 1 and 2 and 4

Results: 30 hits

L8 716/\$.ccls. or 703/2.ccls. or 706/12-13,45-62,919-921.ccls.

L9 1 and 4

Results: 740 hits

L10 9 and (8 or 703/14-16.ccls.)

Results: 56 hits

L11 (capacitance or resistance or interconnect* or connect* or wiring or wire or conductor) and 10

Results: 8 hits

US 20030018457 A1 US-PGPUB Lett, Gregory Scott et al. 703/11

US 6446027 B1 USPAT O'Keeffe, Thomas Gary et al. 702/183

US 4839823 A USPAT Matsumoto, Yoshihiro 706/52

US 5642296 A USPAT Saxena, Sharad 702/84

US 5822218 A USPAT Moosa, Mohamed S. et al. 716/4

US 5276632 A USPAT Corwin, Thomas L. et al. 703/2

US 20020075383 A1 US-PGPUB Trobaugh, Jason W. et al. 348/42

US 6304836 B1 USPAT Krivokapic, Zoran et al. 703/14

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 (actual or physical or real) same (measur\$6 or extract\$4 or determin\$6 or get\$4 or obtain\$3)

L2 bayesian

L3 (capacitance or resistance or interconnect* or connect* or wiring or wire or conductor) and 1 and 2

Results: 0 hits

L4 1 and 2

Results: 8 hits

NN9107436

IBM_TDB

Database Searched: IEE/IEEE Xplore

Terms Searched: ((actual or physical or real) <near/10> (measur* or extract* or determin* or get* or obtain*)) and (physic <near/10> model*) and bayesian

Results: Your search matched 1 of 945031 documents.

Terms Searched: measur* and bayesian and (capacitance or resistance or interconnect* or connect* or wiring or wire or conductor)

Results: Your search matched 27 of 945031 documents.

Terms Searched: measur* and bayesian and (capacitance or resistance or interconnect* or connect* or wiring or wire or conductor)

Results: Your search matched [0] of [945031] documents.

Terms Searched: measur* and bayesian and (capacitance or resistance or interconnect* or connect* or wiring or wire or conductor) and electric*

Results: Your search matched 2 of 943290 documents.

Terms Searched: bayesian and (electri* or circuit)

Results: Your search matched 123 of 945031 documents.

Terms Searched: bayesian and (electri* or circuit) and capacit*

Results: Your search matched 5 of 945031 documents.

Terms Searched: bayesian and (electri* or circuit) and (interconnect* or wiring or wire or routing)

Results: Your search matched 1 of 945031 documents.

Terms Searched: bayesian and (electri* or circuit) and resist*

Results: Your search matched 2 of 945031 documents.

Niu, et al., "A Bayesian Approach to Variable Screening for Modeling the IC Fabrication Process," Circuits & Systems, 1995 IEEE Int'l Symposium, pp. 1227-1230.